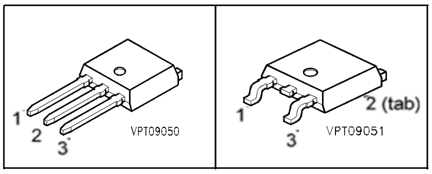
Cool MOS™ Power Transistor

V_{DS} @ T_{jmax}	650	V
$R_{DS(on)}$	0.6	Ω
I_D	7.3	A

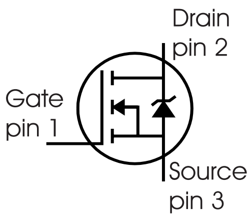
PG-TO251 PG-TO252



Feature

- New revolutionary high voltage technology
- Worldwide best $R_{DS(on)}$ in TO-251 and TO-252
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- High peak current capability
- Improved transconductance
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC[0)] for target applications

Type	Package	Ordering Code	Marking
SPD07N60C3	PG-TO252	Q67040-S4423	07N60C3
SPU07N60C3	PG-TO251		07N60C3



Maximum Ratings

Parameter	Symbol	Value	Unit
Continuous drain current	I_D		A
T_C = 25 °C		7.3	
T_C = 100 °C		4.6	
Pulsed drain current, t_p limited by T_{jmax}	$I_{D\ puls}$	21.9	
Avalanche energy, single pulse I_D = 5.5 A, V_{DD} = 50 V	E_{AS}	230	mJ
Avalanche energy, repetitive t_{AR} limited by T_{jmax}[1)] I_D = 7.3 A, V_{DD} = 50 V	E_{AR}	0.5	
Avalanche current, repetitive t_{AR} limited by T_{jmax}	I_{AR}	7.3	A
Reverse diode dv/dt [6)]	dv/dt	15	V/ns
Gate source voltage static	V_{GS}	±20	V
Gate source voltage AC (f >1Hz)	V_{GS}	±30	
Power dissipation, T_C = 25°C	P_{tot}	83	W
Operating and storage temperature	T_j , T_{stg}	-55... +150	°C

Maximum Ratings

Parameter	Symbol	Value	Unit
Drain Source voltage slope V_{DS} = 480 V, I_D = 7.3 A, T_j = 125 °C	dv/dt	50	V/ns

Thermal Characteristics

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Thermal resistance, junction - case	R_{thJC}	-	-	1.5	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	75	
SMD version, device on PCB: @ min. footprint @ 6 cm² cooling area [2)]	R_{thJA}	 - -	 - -	 75 50	
Soldering temperature, *) 1.6 mm (0.063 in.) from case for 10s [3)]	T_{sold}	-	-	260	°C

Electrical Characteristics, at Tj=25°C unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Drain-source breakdown voltage	$V_{(BR)DSS}$	V_{GS}=0V, I_D=0.25mA	600	-	-	V
Drain-Source avalanche breakdown voltage	$V_{(BR)DS}$	V_{GS}=0V, I_D=7.3A	-	700	-	
Gate threshold voltage	$V_{GS(th)}$	I_D=350µA, V_{GS}=V_{DS}	2.1	3	3.9	
Zero gate voltage drain current	I_{DSS}	V_{DS}=600V, V_{GS}=0V, T_j=25°C, T_j=150°C	 - -	 0.5 -	 1 100	µA
Gate-source leakage current	I_{GSS}	V_{GS}=30V, V_{DS}=0V	-	-	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V_{GS}=10V, I_D=4.6A, T_j=25°C T_j=150°C	 - -	 0.54 1.46	 0.6 -	Ω
Gate input resistance	R_G	f=1MHz, open Drain	-	0.8	-	

*) TO252: reflow soldering, MSL3; TO251: wavesoldering

Electrical Characteristics , at T_j = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Transconductance	g_{fs}	V_{DS}≥2*I_D*$R_{DS(on)max}$, I_D=4.6A	-	6	-	S
Input capacitance	C_{iss}	V_{GS}=0V, V_{DS}=25V, f=1MHz	-	790	-	pF
Output capacitance	C_{oss}		-	260	-	
Reverse transfer capacitance	C_{rss}		-	16	-	
Effective output capacitance,[4] energy related	$C_{o(er)}$	V_{GS}=0V, V_{DS}=0V to 480V	-	30	-	pF
Effective output capacitance,[5] time related	$C_{o(tr)}$		-	55	-	
Turn-on delay time	$t_{d(on)}$	V_{DD}=380V, V_{GS}=0/13V, I_D=7.3A, R_G=12Ω, T_j=125°C	-	6	-	ns
Rise time	t_r		-	3.5	-	
Turn-off delay time	$t_{d(off)}$		-	60	100	
Fall time	t_f		-	7	15	

Gate Charge Characteristics

Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Gate to source charge	Q_{gs}	V_{DD}=480V, I_D=7.3A	-	3	-	nC
Gate to drain charge	Q_{gd}		-	9.2	-	
Gate charge total	Q_g	V_{DD}=480V, I_D=7.3A, V_{GS}=0 to 10V	-	21	27	
Gate plateau voltage	$V_{(plateau)}$	V_{DD}=480V, I_D=7.3A	-	5.5	-	V

[0]J-STD20 and JESD22

[1]Repetitve avalanche causes additional power losses that can be calculated as P_{AV}=E_{AR}*f.

[2]Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 µm thick) copper area for drain connection. PCB is vertical without blown air.

[3]Soldering temperature for TO-263: 220°C, reflow

[4]$C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.

[5]$C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.

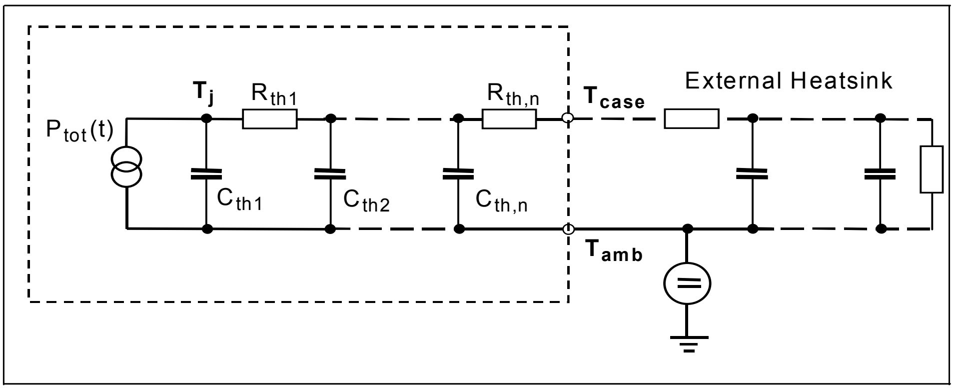
[6]I_{SD}<=I_D, di/dt<=400A/us, V_{DClink}=400V, V_{peak}<$V_{BR, DSS}$, T_j<$T_{j,max}$.
Identical low-side and high-side switch.

Electrical Characteristics, at T_j = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Inverse diode continuous forward current	I_S	T_C=25°C	-	-	7.3	A
Inverse diode direct current, pulsed	I_{SM}		-	-	21.9	
Inverse diode forward voltage	V_{SD}	V_{GS}=0V, I_F=I_S	-	1	1.2	V
Reverse recovery time	t_{rr}	V_R=480V, I_F=I_S ,	-	400	600	ns
Reverse recovery charge	Q_{rr}	di_F/dt=100A/µs	-	4	-	µC
Peak reverse recovery current	I_{rrm}		-	28	-	A
Peak rate of fall of reverse recovery current	di_{rr}/dt		-	-	800	A/µs

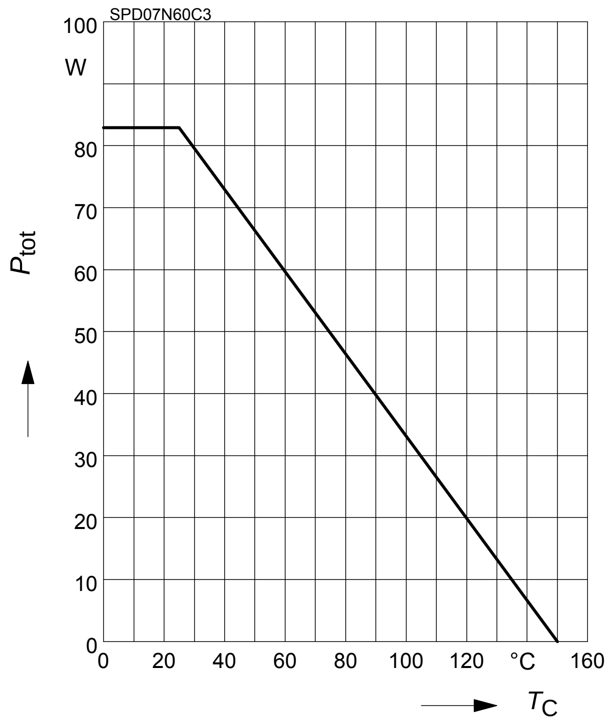
Typical Transient Thermal Characteristics

Symbol	Value	Unit	Symbol	Value	Unit
	typ.			typ.	
Thermal resistance			Thermal capacitance		
R_{th1}	0.024	K/W	C_{th1}	0.00012	Ws/K
R_{th2}	0.046		C_{th2}	0.0004578	
R_{th3}	0.085		C_{th3}	0.000645	
R_{th4}	0.308		C_{th4}	0.001867	
R_{th5}	0.317		C_{th5}	0.004795	
R_{th6}	0.112		C_{th6}	0.045	



1 Power dissipation

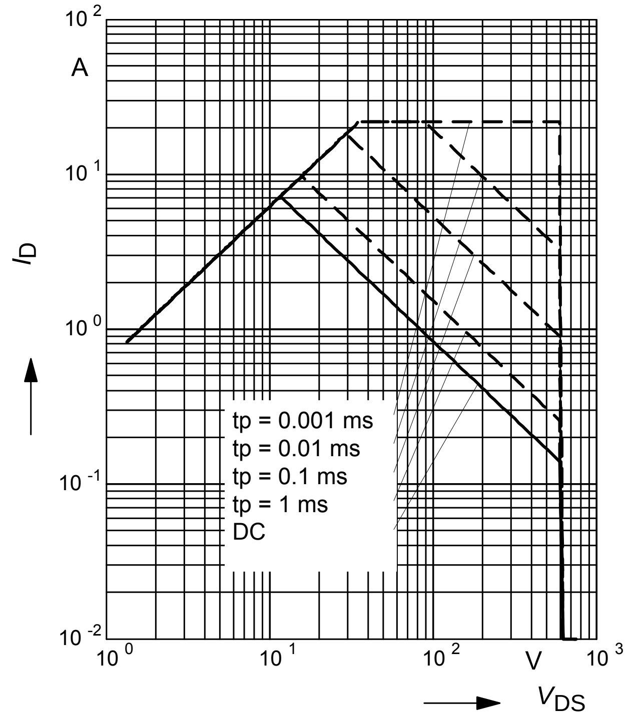
$P_{tot} = f(T_C)$



2 Safe operating area

$I_D = f(V_{DS})$

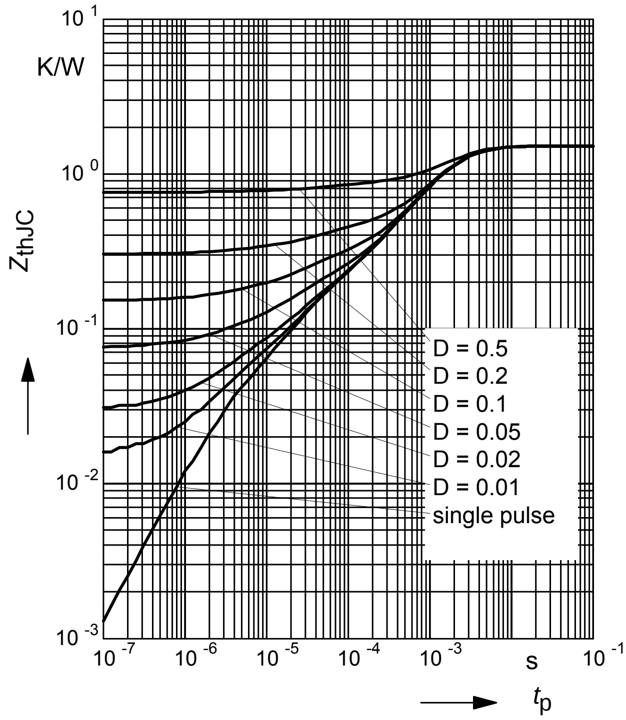
parameter : $D = 0$, T_C=25°C



3 Transient thermal impedance

$Z_{thJC} = f(t_p)$

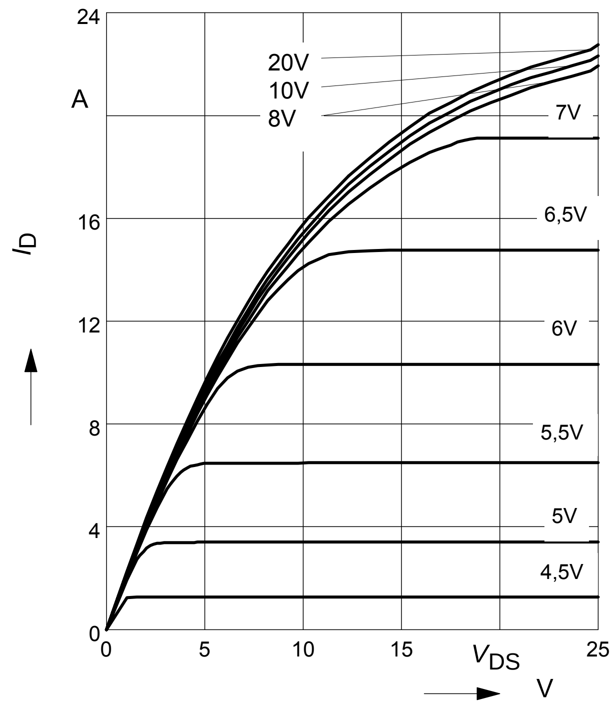
parameter: $D = t_p/T$



4 Typ. output characteristic

$I_D = f(V_{DS})$; T_j=25°C

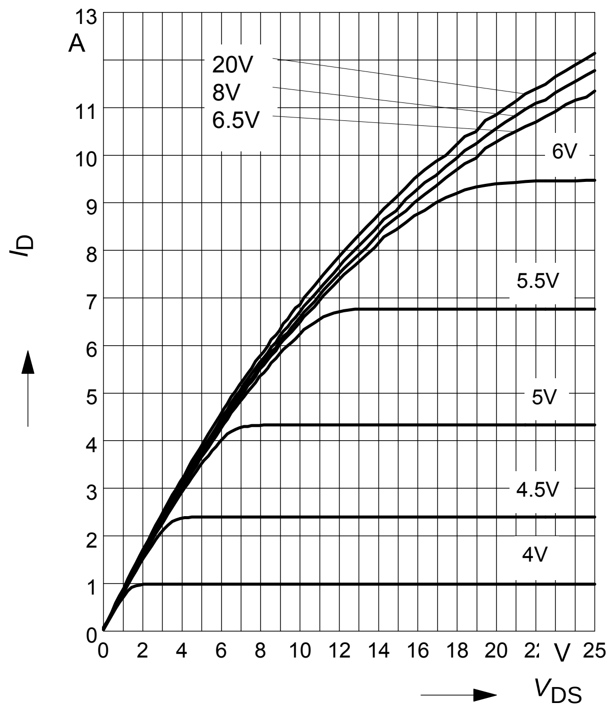
parameter: t_p = 10 µs, V_{GS}



5 Typ. output characteristic

$I_D = f(V_{DS})$; T_j=150°C

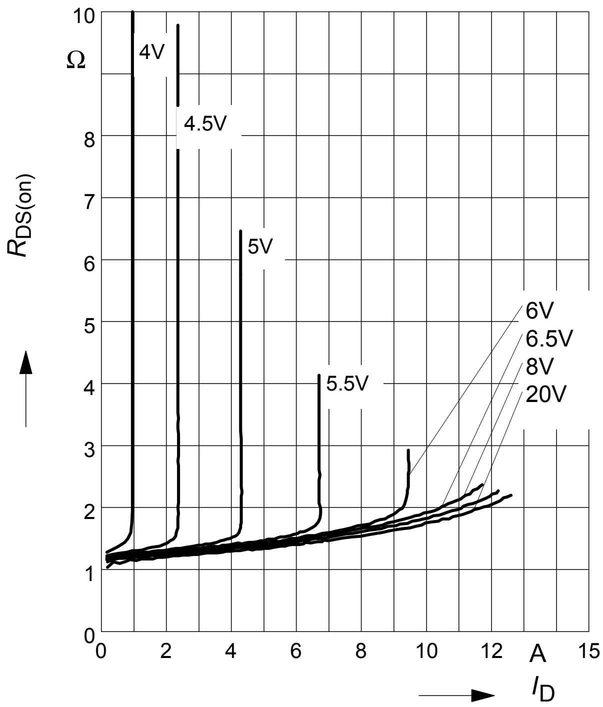
parameter: t_p = 10 µs, V_{GS}



6 Typ. drain-source on resistance

$R_{DS(on)}=f(I_D)$

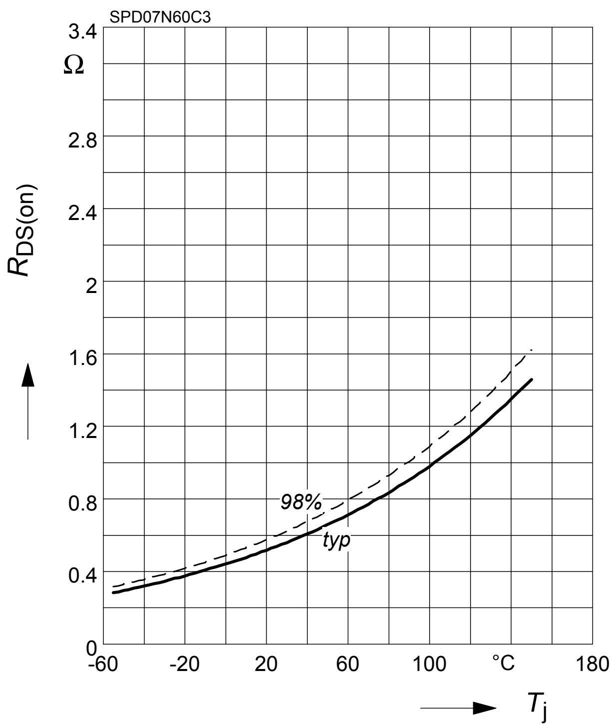
parameter: T_j=150°C, V_{GS}



7 Drain-source on-state resistance

$R_{DS(on)} = f(T_j)$

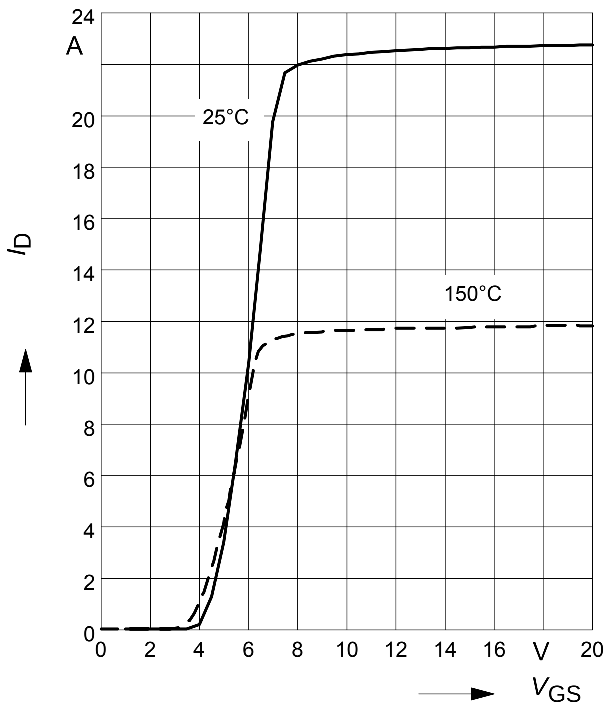
parameter : I_D = 4.6 A, V_{GS} = 10 V



8 Typ. transfer characteristics

$I_D= f(V_{GS})$; $V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$

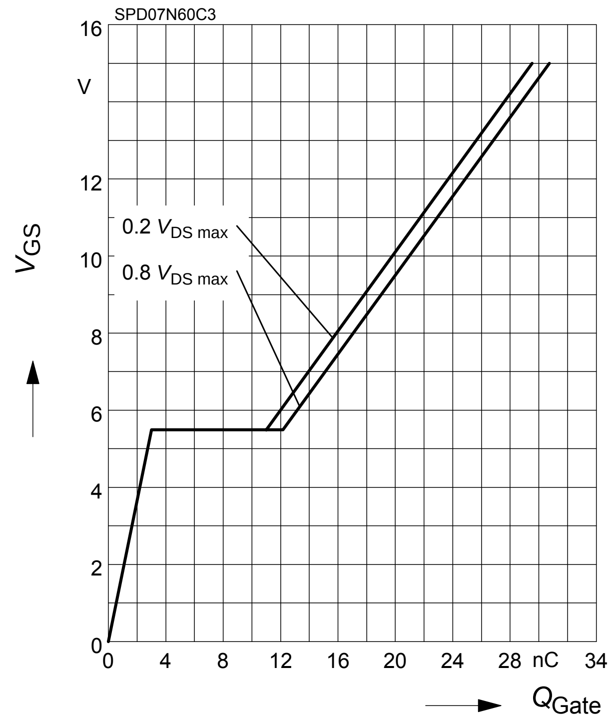
parameter: t_p = 10 µs



9 Typ. gate charge

$V_{GS} = f\ (Q_{Gate})$

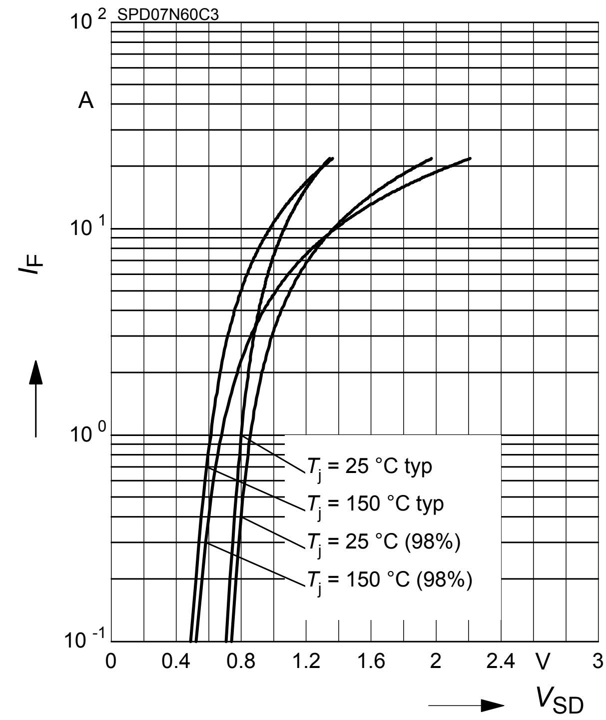
parameter: I_D = 7.3 A pulsed



10 Forward characteristics of body diode

$I_F = f\ (V_{SD})$

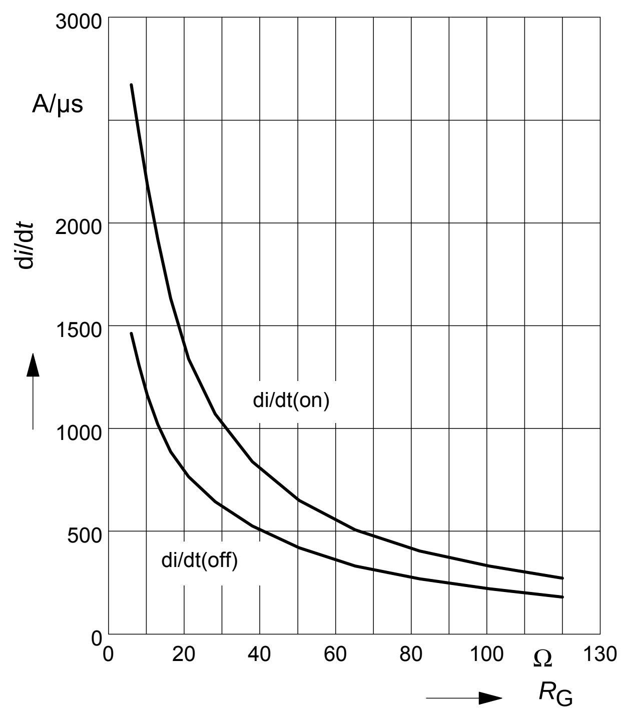
parameter: T_j , t_p = 10 µs



11 Typ. drain current slope

di/dt = f(R_G), inductive load, T_j = 125°C

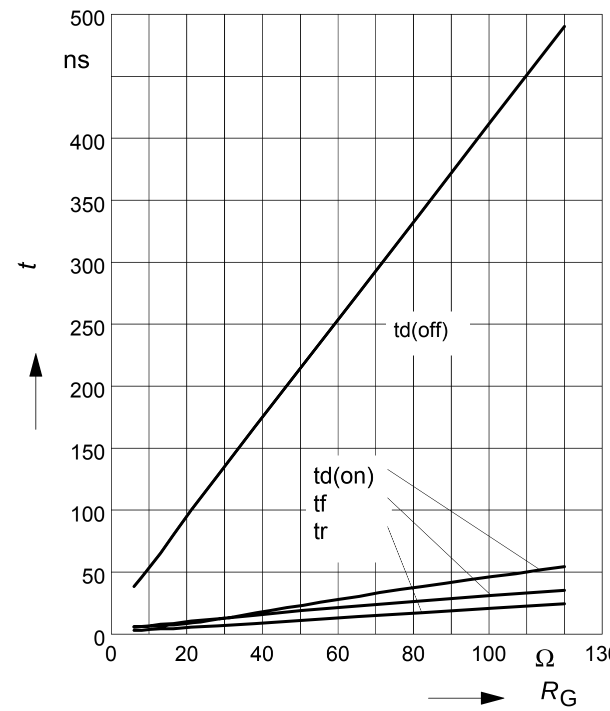
par.: V_{DS}=380V, V_{GS}=0/+13V, I_D=7.3A



12 Typ. switching time

$t = f\ (R_G)$, inductive load, T_j=125°C

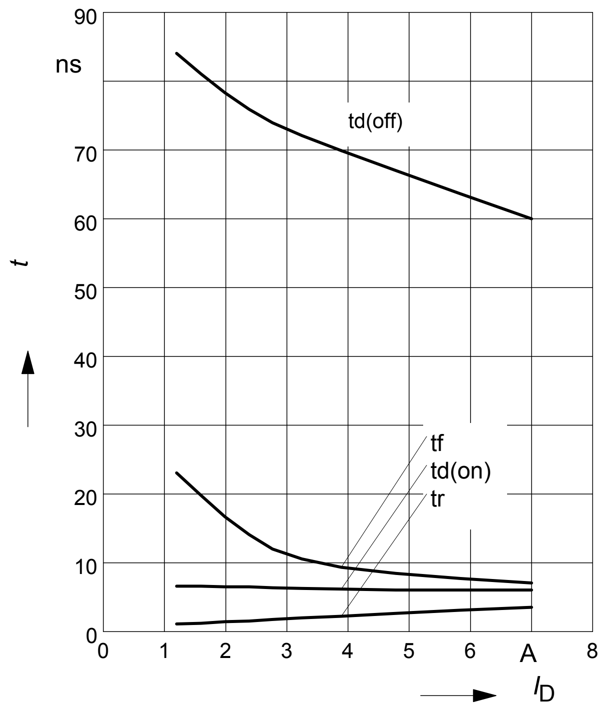
par.: V_{DS}=380V, V_{GS}=0/+13V, I_D=7.3 A



13 Typ. switching time

$t = f(I_D)$, inductive load, T_j=125°C

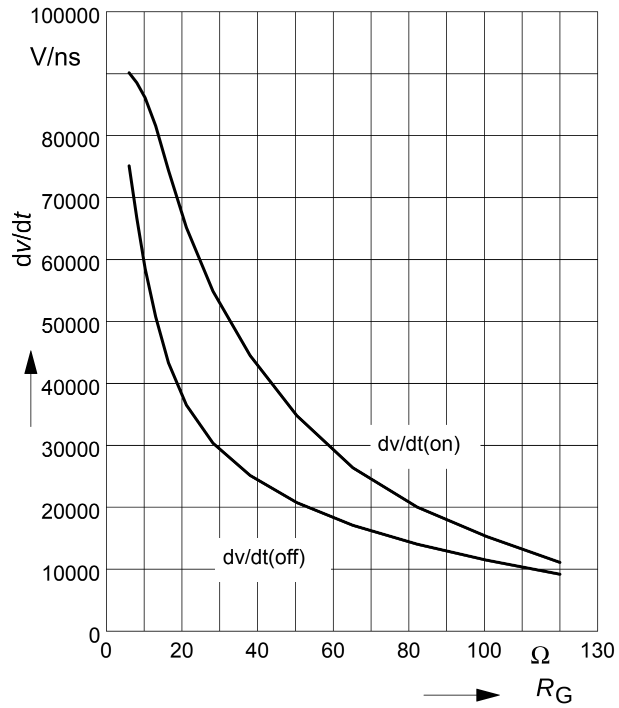
par.: V_{DS}=380V, V_{GS}=0/+13V, R_G=12Ω



14 Typ. drain source voltage slope

$dv/dt = f(R_G)$, inductive load, T_j = 125°C

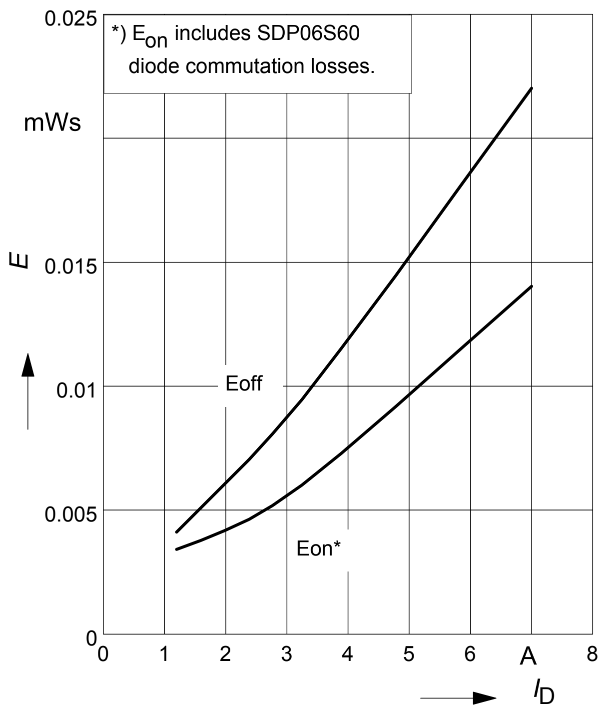
par.: V_{DS}=380V, V_{GS}=0/+13V, I_D=7.3A



15 Typ. switching losses

$E = f(I_D)$, inductive load, T_j=125°C

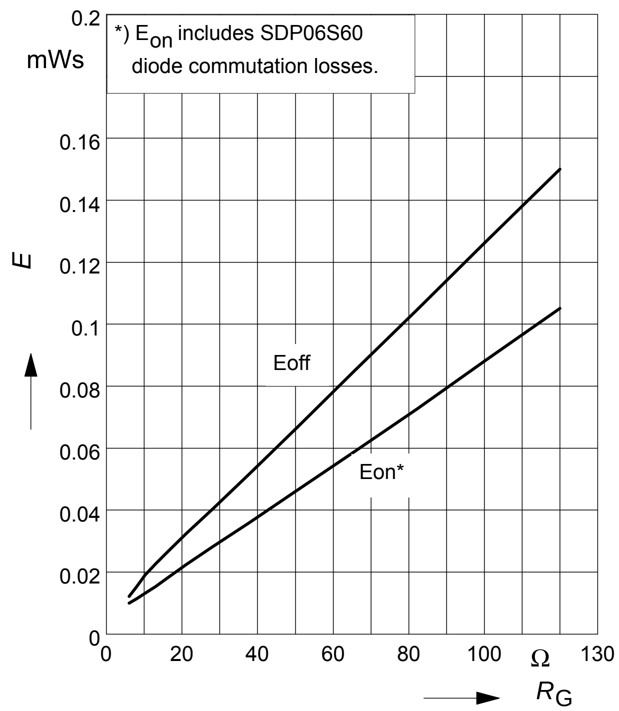
par.: V_{DS}=380V, V_{GS}=0/+13V, R_G=12Ω



16 Typ. switching losses

$E = f(R_G)$, inductive load, T_j=125°C

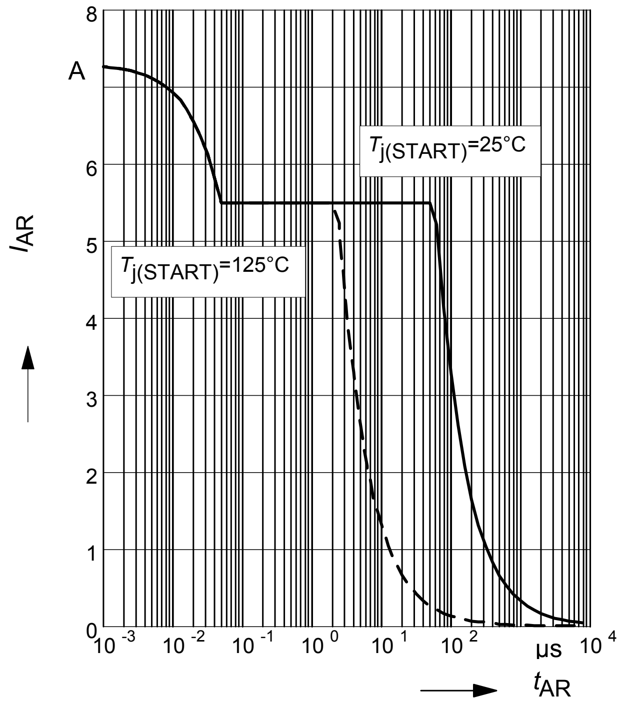
par.: V_{DS}=380V, V_{GS}=0/+13V, I_D=7.3A



17 Avalanche SOA

$I_{AR} = f(t_{AR})$

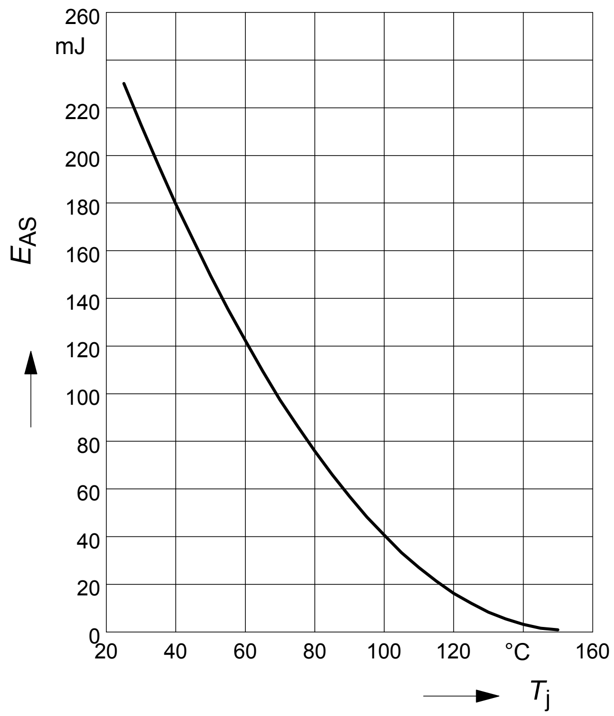
par.: $T_j \leq 150$ °C



18 Avalanche energy

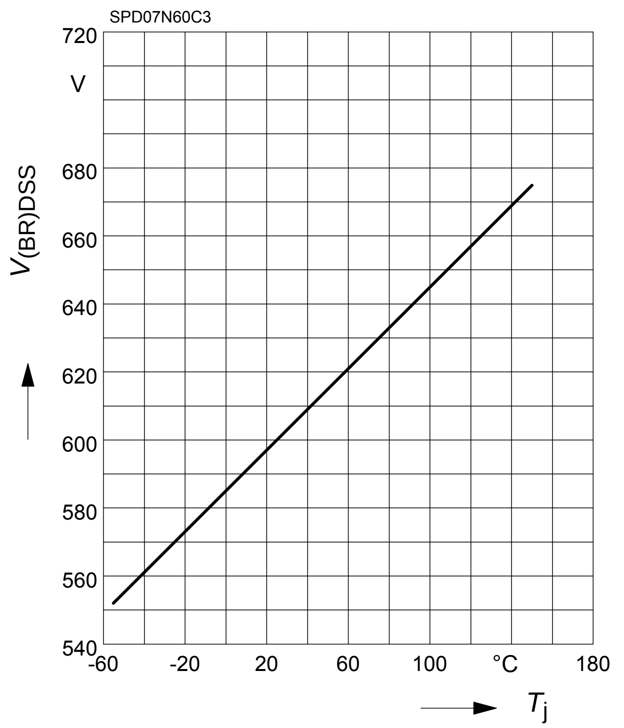
$E_{AS} = f(T_j)$

par.: I_D = 5.5 A, V_{DD} = 50 V



19 Drain-source breakdown voltage

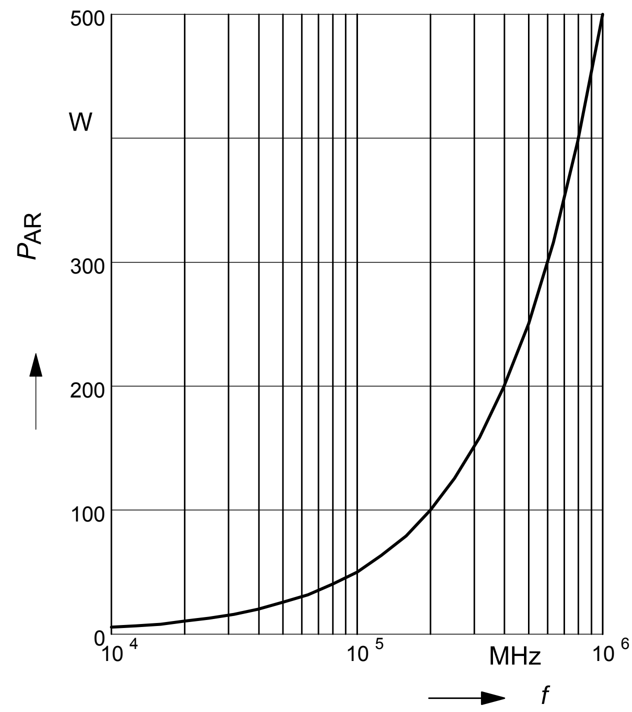
$V_{(BR)DSS} = f(T_j)$



20 Avalanche power losses

$P_{AR} = f(f)$

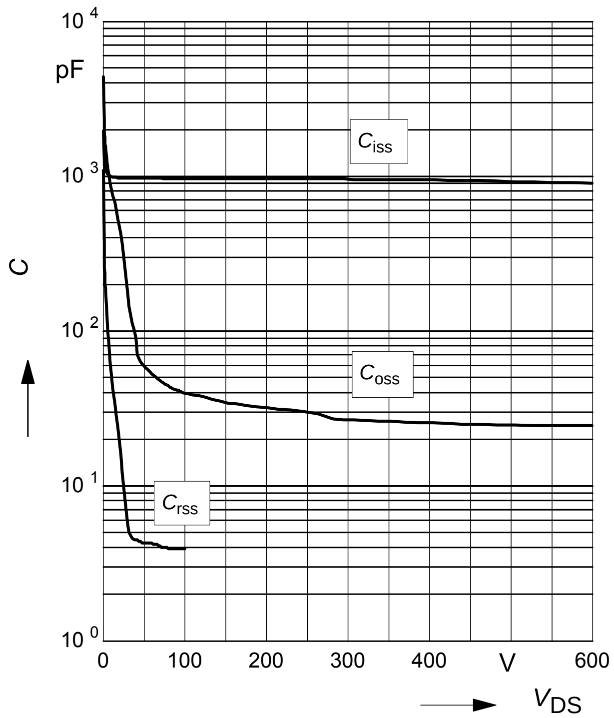
parameter: E_{AR}=0.5mJ



21 Typ. capacitances

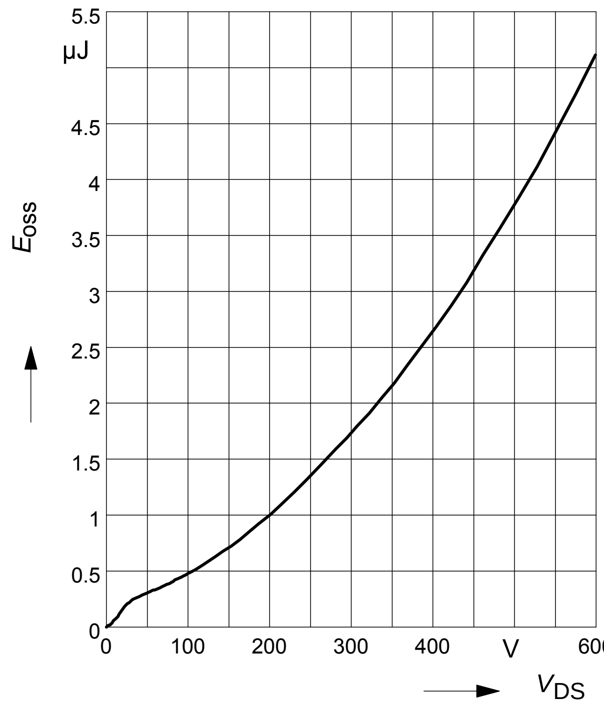
$C = f(V_{DS})$

parameter: V_{GS}=0V, f=1 MHz

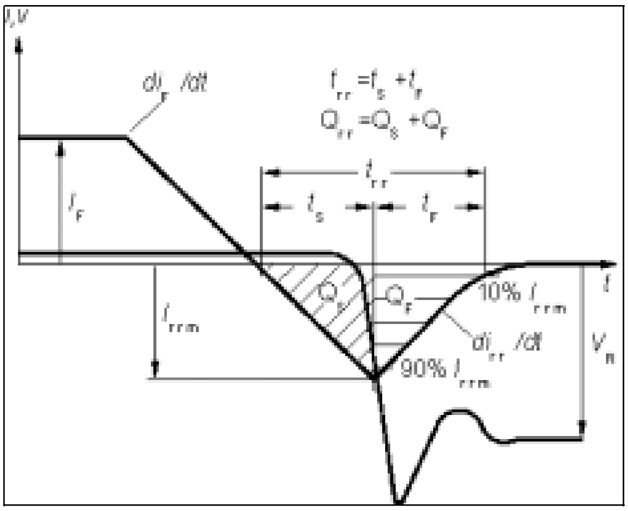


22 Typ. C_{oss} stored energy

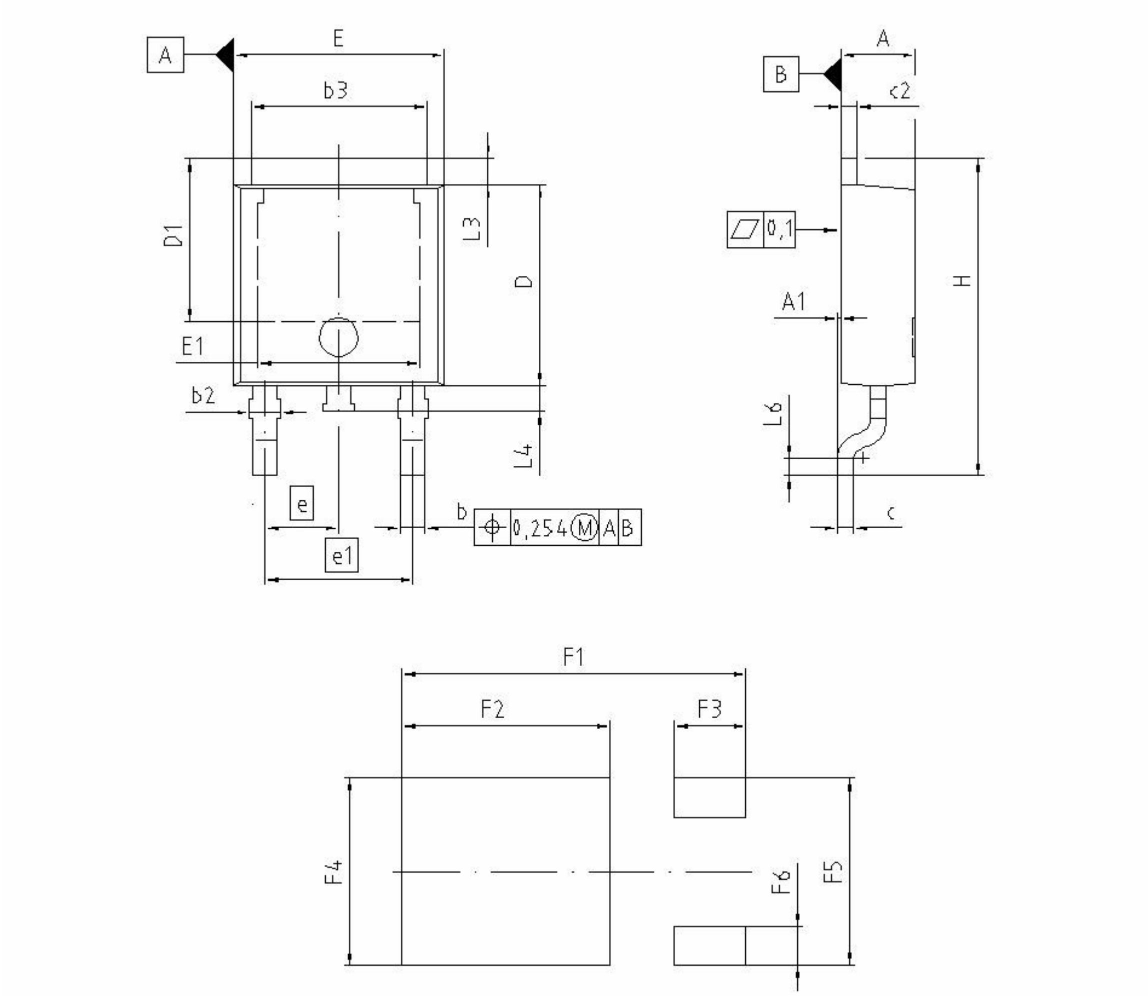
$E_{oss}=f(V_{DS})$



Definition of diodes switching characteristics



PG-TO-252-3-1 (D-PAK), PG-TO-252-3-11 (D-PAK), PG-TO-252-3-21 (D-PAK)



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.159	2.413	0.085	0.095
A1	0.000	0.150	0.000	0.006
b	0.635	0.889	0.025	0.035
b2	0.650	1.150	0.026	0.045
b3	5.004	5.500	0.197	0.217
c	0.457	0.580	0.018	0.023
c2	0.460	0.980	0.018	0.039
D	5.969	6.223	0.235	0.245
D1	5.020	5.842	0.198	0.230
E	6.400	6.731	0.252	0.265
E1	4.850	5.207	0.191	0.205
e	2.286		0.090	
e1	4.572		0.180	
N	3		3	
H	9.400	10.480	0.370	0.413
L3	0.900	1.143	0.035	0.045
L4	0.584	0.950	0.023	0.037
L6	0.510	0.686	0.020	0.027
F1	10.500	10.700	0.413	0.421
F2	6.300	6.500	0.248	0.256
F3	2.100	2.300	0.083	0.091
F4	5.700	5.900	0.224	0.232
F5	5.660	5.860	0.222	0.231
F6	1.100	1.300	0.043	0.051

REFERENCE
JEDEC TO252

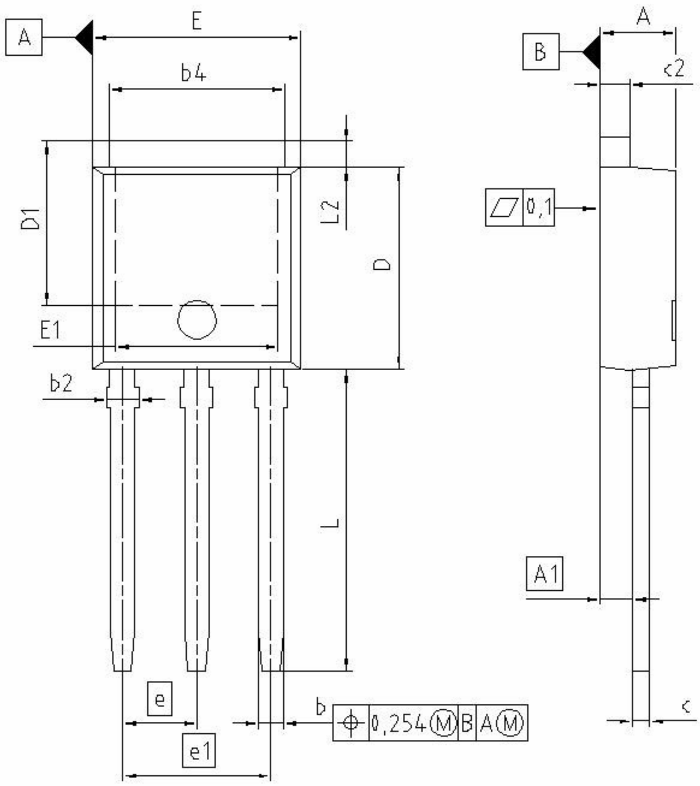
SCALE
0 2.0 4mm

EUROPEAN PROJECTION

ISSUE DATE
21-09-2005

FILE
TO252_1

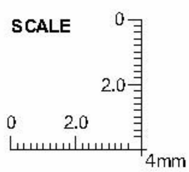
PG-TO-251-3-1 (I-PAK), PG-TO-251-3-21 (I-PAK)



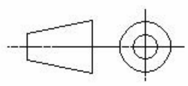
DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.159	2.413	0.085	0.095
A1	0.900	1.118	0.035	0.044
b	0.650	0.850	0.026	0.033
b2	0.650	1.150	0.026	0.045
b4	5.004	5.500	0.197	0.217
c	0.457	0.580	0.018	0.023
c2	0.737	0.980	0.029	0.039
D	5.969	6.223	0.235	0.245
D1	5.100	6.121	0.201	0.241
E	6.400	6.731	0.252	0.265
E1	4.850	5.207	0.191	0.205
e	2.280		0.090	
e1	4.570		0.180	
N	3		3	
L	8.900	9.525	0.350	0.375
L1	0.900	1.143	0.035	0.045

REFERENCE
JEDEC TO251

SCALE



EUROPEAN PROJECTION



ISSUE DATE
20-07-2005

FILE
TO251_1

Published by
Infineon Technologies AG
81726 München
Germany

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